UNIVAC SEMICONDUCTOR TEST RECORD: Approx. 1957 to 1962

A component test and evaluation lab was set up for the purpose of determining which products met Univac military application requirements and were acceptable for use in Univac equipment. The lab itself was located in Plant 3, then Plant 1, and finally Plant 2. Each request for test was entered on a log sheet. This document shows selected log sheets from a collection held by Don D. Johnson who was head of the component test and evaluation lab for 35 years. It shows the names of semiconductor suppliers in business during the 1957 to 1962 timeframe and the types of tests that the component test lab was asked to perform on the new technology. The blank form carries an ERA form number (ERA-1037). Note the reference to 'Diode', 'Triode', and 'Tetrode'. None of the records show any 'tetrode' semiconductors were ever tested.

Early requests were logged on an EF1059 semiconductor test form. About 1957, it was decided that a different numbering system was to be used. Thus began the PX72000 series of test numbers. After reviewing all the test records, it appears the following date ranges are applicable:
PX72000-1000 thru 1480: These tests were originally entered on the EF1059 form. Those EF1059 tests still in process were assigned a PX72000 series number and re-entered on the new record form after its use had begun. This is the reason these are not the lowest test numbers but may be the earliest tests. These tests span the years 1957 and 1958
PX72000-11 to 540: These mark the beginning of the PX72000 series of formal test numbers. The tests numbered 11 to 999 also cover the years 1957 and 1958. How and why they appear to overlap time-wise with the PX72000-1000 series is not clear.
PX72000-545 to 999: 1958
Skipping over the 1000 to 1480 block used by the earlier tests.
PX72000-1481 to 1644: 1958 continued
PX72000-1650 to 2354: 1959
PX72000-2355 to 2953: 1960
PX72000-2957 to 3490: 1961
PX72000-3494 to 3606: thru April 1962 at which point this log was no longer used.
The PX72000 series of formal report numbers continued to be used well into the 1990's. The reports were all formal reports, including a summary of results or conclusion and having a supervisor or manager signoff

The following sheets are included in this sampling:
Amperex – sheet 1 of 1 (note test 29 requested by J. L. Hill)
Bendix – sheet 1 of 1
Clevite – sheet 1 of 5
CBS – sheet 1 of 3
Delco – sheet 1 of 1
Fairchild – sheet 1 of 3
Federal – sheet 1 of 1
Gahagan – sheet 1 of 1
General Electric – sheet 1 of 6
General Instrument – sheet 1 of 1
General Transistor – sheet 1 of 6
Hoffman – sheet 1 of 1

Hughes – sheet 1 of 5
IRC – sheet 1 of 1
Motorola – sheet 1 of 3 (comment on PX 1084, transistor cost would have been $350 for 10 samples)
Ohmite – sheet 1 of 1
Pacific Semiconductor – sheet 1 of 2
Philco – sheets 1 and 2 of 7
RCA – sheet 1 of 5 (first entry is PX72000-11, lowest number on any sheet)
Radio Receptor – sheet 1 of 2
Raytheon – sheets 1 and 2 of 3
Rheem – sheet 1 of 1
Semcor – sheet 1 of 1
Sperry – sheet 1 of 2
Sprague – sheet 1 of 1
Sylvania – sheets 1 and 2 of 6
Texas Instruments – sheet 1 of 6
T. P. – sheet 1 of 1
Transitron – sheet 1 of 7
Tung Sol – sheet 1 of 2
Western Electric – sheet 1 of 6
Westinghouse – sheet 1 of 1
Miscellaneous – all sheets (shows numerous other suppliers that do not have separate sheets)

Scanned and archived on 12/2/2009 by the VIP Club Legacy Committee. Originals returned to Don Johnson.

AMPEREX

SEMICOND[illegible] TEST RECORD

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	QUANTITY	DIODE	TRIODE	TETRODE	OTHER MFGR	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST PARAM.	TEST LIFE	SUMMARY	COMPLETE	REMARKS
29		J L Hill	10	X			Also 9 Other Mfgr.	1N58A	1-76005	6-25				6/25	Humidity & Temp Cycling
46		D OMAN	6	X			Also Others	1N58A	1-76005	1-7				1/7	" " "
46B		D OMAN	6	X			Also Others	1N58A	1-76005	1-7				1/7	" " "
107A		RB ARNDT	5	X			ALSO OTHERS	1N58A	3035-39-021	11/15				11/16	Power Dissipation
528	12/6	R Kerler	20ea.	X			Also Others	S58	8428135	3/16		3/9			Vendor Screening
857A	8-22	EP Deeb 8/26	1	X			Various	V900171	6221104	11/11	9/22		11/26	11/26	Failure Analysis
1140			10	X				OA5			4/24		4/24	5/23	
1211			8	X				1N67A			7/3		7/3	7/15	Against 900179 (Comm) 900448 (Mil)
1265			12		X			2N284A			11/7		11/22	11/25	Capability Against 902908
1266			12		X			2N284A			11/6		11/22	11/25	" " 903212A
1299		RJK Has Units	20	X				U900171C (S-581)			12/13		12/16	12/17	" " 900171C
1365	12/6		20	X				S58			1/30		8/22	8/22	Design & Spec Info (900171)
1627	12-23	AA Kaine	60	X			Trans CBS-CTP	900181	613120	6-13-61		4/1	5/20	5/25	Life test
1714	1-30	CA Johnson	100	X				S-58	613120	6-13-61	3/13		3/14	5/12	Eval. Mech. & Elec. Life test Char.
2367	1-8	G.F. Goodrich	195		X			Philips OC169	818100	1-25	1/25				Parameters & Hermetic Seals

Formerly EF 1059

GG GG GG

AMPEREX

ERA-1037

SEMICONDUCTOR TEST RECORD

BENDIX

PAGE I

	PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
	999	10-23	R.H. MESS		23		X			2N677C	359281	2-4	12/24		1/16	1/16	Evaluation
J.K.	1539	10-30	RH Ness	11/4	30		X			2N174-DT100-2N677C	359281	2-5	3/5		3/17	3/20	MW/°C
JK	1812	3-17	RH Ness	3/13	25		X			2N637B	359281	4-17	3/26		5/8	5/12	Plots - HST
JK	1813	4-17	RH Ness	3/16	46		X			2N637B	359281	10-14		8/10			" Lifetest
JK	1814	4-17	RH Ness	3/16	66		X			2N677C	359281	10-14		8/10			" Lifetest

BENDIX

ERA-1037

SEMICONDUCTOR TEST RECORD

CLEVITE PAGE I

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST PARAMETER	TEST LIFE	SUMMARY	COMPLETE	REMARKS
206				25ea.	X			Other	1N58A 279		8-2				9/2	Reliability
347				12	X			Other	1N143		3/8				3/8	Stability Char.
386				50	X			Other	GA41		10/11				10/11	Shelf life
453	8/26			20	X			Trans	1N207-CTP307		3/6	3/6	3/6	3/6	3/6	High Temp under pulse
461	8/9			300	X				CTP442		9/7	9/7	9/7	9/7	9/7	Vibration, Shock, Soldering
523	12/2			100	X			Other	RRU111318		—	8/7	8/7	8/11	8/11	Vibration-life
524				75	X			Hughes Trans	CTP2302		—	1/16		8/15	8/15	Vendor screening
527				75	X			Other	CTP453		—	1/14		8/11	8/11	" "
528	12/6			20	X			Other	1N58A		3/16	/	3/9			" "
531	12/6			25	X			Other	CTP453		9-10	1/10		8/15	8/15	Temp storage
532	12/6			75	X			Other	CTP494		—	6/17		8/8	8/8	Vendor screening
609	4/15			100	X			Hughes	CTP558		4/28	4/28		4/28	4/28	Vibration Effects
634	6/4			1000	X				CTP558			9/2		9/9	9/9	Failure vs. Shock & Vibration
857 A B	8/22			170	X			Other	3-V-numbers		11/11	9/22		11/26	11/26	Failure analysis
967	10/14			100	X			Hughes	V900171			10/22		1/16	1/16	Prov. data for stat anal.
978	10/14			745	X			CBS	V900172		11/11	11/10		12/5	12/5	Failure analysis
993	10/23			139	X				V900171	7-10	11/11	11/10		11/18	11/18	" "
994	10/23			94	X			Other	V900171	7-10		11/11		11/21	11/21	" "
995	10/23			16	X			Other	V900152	7-10		11/11		11/20	11/20	" "
1187	5/22			100	X				CTP453			5/22		5/24	6/19	200 units [illegible] Against 900181
1207	6/24			300	X				CTP453			6/27		6/27	7/8	2067 for Shelley
1209	6/26			20	X				CTP494			7/26		7/2	7/15	Against 901466
1218	7/12	Units returned to L. Grantberg		10	X			Hughes Trans	CTP442			7/17		7/30	8/1	Capability
1288				12	X				CTP2302			10/14		10/15	10/25	"
1291		Units returned to J.L. Moe		17	X				1N278			11/19		12/3	12/6	Capability & stability
1292		"		25	X				1N277			11/20		12/4	12/9	" "

Formerly EF 1069

CLEVITE I

ERA-1037

SEMICONDUCTOR TEST RECORD

C BS

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST PARAMETER	TEST LIFE	SUMMARY	COMPLETE	REMARKS
97				12	X			Other	1N58A		6/30				6/30	Humidity & Temp Cycling
107A				2		X		Other	HD 197		10/10				10/10	Power dissipation
155				9	X			other	1N291		5/8				5/8	Pulsed Operation
166				12	X			other	1N58A		3/12				3/12	Comparison
206				14	X			other	S29		8/2				8/2	Reliability
231				10ea		X		Trans	HD419 · HD420		12/6				12/6	Operational Life
306				20ea		X			2N182 - 2N183 2N184		4/4				4/4	Temp Cycle
528	12/6			20	X			Other	1N58AG		3/16		3/9			Vendor screening
686	8/7	R Kerler	7/14	75	X				(V900172C) LD123	8532/04	25 - 10/6 50 - 6/12	10/2		1/28	1/28	Hermetic seal, dip solder, shock
857A	8/22	E P Deeb	8/26	2	X			other	V900171	6221104	11-11	9/22		11/26	11/26	Failure analysis
978	10/14	E P Deeb	8/13	68	X			Clevite	V900172	6222104	1-12	11/11		12/5	12/5	" "
994	10/23	E P Deeb		15	X			other	V900171	6222104	7-10	11/11		11/21	11/21	" "
1001	—	Cancelled	—	10		X			HD402 —	Cancelled —	—	—			1/29	P.O. Cancelled 1/29
1010	6/27			4		X			2N182			3/29		4/29	4/29	
1011	6/27			10		X			2N183			12/28		1/3	1/3	
1012	11/23			5		X			2N184			12/3		12/6	2/12	
1066	12/18			2		X			2N255			5/9		5/13	5/13	2 Sent to Thorndyke
1067	12/18			3		X			2N256			5/9		5/13	5/13	" " " "
1073	12/17			6	X				1N497			1/25		2/4	5/21	
1092	1/4			50		X			DT56			1/5		2/12	2/12	Equiv to Syl UFC 905
1093	1/4			50		X			DT57			1/5		2/12	2/12	" " " " 903
1113				13 Selected Units		X			DT56 (905)			1/18		5/23	5/23	(Selected from
1114				Selected 19 Units		X			DT57 (903)			1/18		4/2	4/2	Tests 1092, 1093)
1188	5/17			12	X				901468			5/23		6/13	6/17	Formerly PX500-1
1296		RJK Has Units		20	X				(1N58AG) V900171C			11/26		12/16	12/17	Capability 900171
1332				12	X				1N597			1/9		2/5	2/6	" 901466

CBS

Formerly EF 1059

SEMICONDUCTOR TEST RECORD

DELCO

PAGE I

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	QUANTITY	DIODE	TRIODE	TETRODE	OTHER MFGR	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST PARAM.	TEST LIFE	SUMMARY	COMPLETE	REMARKS
817	8/11		5		X			2N174		4-19	8/26		9/25	9/25	Specification Info
828	8/12		1		X			2N174		8/19	7/12		8/26	8/26	Failed Component
889	9/8		3		X			2N553			9/23		10/2	10/2	Comparison W.E. GA 53242
925	9/30		50		X			2N174, DT100		2-4	10/23		11/6	11/6	Plots
941	9/30		1		X			2N174		10/21	10/7		10/22	10/22	Failure Analysis 10-15
1180 (Formerly EF 1059)	4/29		6		X			902834			6/24		8/12	8/12	
1425		Units returned to L. Grandberg	11		X			184487			4/22		5/4	5/13	Dist. of Elec. parameter
1426		"	12		X			2N553			4/23		5/4	5/13	" " " "
1539	10-30	RH Ness	30		X		Bendix	2N174 DT100 2N677C	359281	2-5	2/5		3/17	3/20	MW/°C
1599	12-5	RH Ness	25		X			2N553	359281	4-7	12/22		1/21	1/21	Elec. para.
1613	12-10	KM Hoglund	15		X			2N174	616210	1-6	12/24		1/9	1/9	" "
1644	12-23	KM Hoglund	15		X			902834-D	616210	1-12	1/9		1/28	1/28	" "
1813	4-17	R. Ness	45		X		Bendix	2N637B	359281	10-14		8/10			Life Test - Plots
1814	4-17	R. Ness.	65		X		CTP Bendix	2N677C	359281	10-14		8/10			Life Test - Plots
JK 2163	9-2	K. Hoglund	27		X			V907339A	616210	9-24		9/23			Elect. Parameters, Plots
GC 2267	11-3	B. Bissonette	6		X			V907339A	616210	1-12	11/4				Component Evaluation
JM 2328	12-9	Bissonette	21		X			V907339A	616210	1-9	1/8				Component Evaluation
BNS 2328S	2-3	Bissonette	10		X			V907339A	616210	2-9	2/5				Component Evaluation
HS 2428	2-17	Bissonette	3		X			2N174	616210	2-26	2/26				Component Evaluation
HS 2538	open	D.R. Anderson	3		X			V907339C (2N174)	6823152 616210	6-1	5/31				Elect. Parameters
RG 2570	4-11	R.J. Kerler	47		X			V907339A	616210	7-1	6/21				Elect. Parameters
RI 3393	10-3	K.B. DALAGER	14		X			2N1612 (912307)	998140	10-12-61	10/11				ELECT. PAR.
JK 3429	10-26	K.B. DALAGER	9		X			2N1611 (912827)	998140	11-17-61	11/15				ELECT. PAR.

DELCO

ERA-1037

SEMICONDUCTOR TEST RECORD FAIRCHILD

	PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	OTHER MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST PARAMETER	TEST LIFE	SUMMARY	COMPLETE	REMARKS
Formerly EF1049	1448				2		X			FT4010			6/23		9/22	9/22	Capability
	1564	11-19	RJ Kerler	11/17	18		X			2N697-2N696	616210	12-12	12/11		1/15	1/16	Elec. para.
	1672	1-13	KM Hoglund	1/13	100		X			2N697-2N696	616210	1-16	1/15		3/5	3/20	Comparison
	1688	1-27	PG Hansen	1/26	2		X			2N697	616210	2-16	2/9		2/10	2/16	F.A.
	1842	3-23	R Kerler	3-23	25+20		X			2N696-2N697	616210	4-2	3-27		5/18	5/21	Shock
	1936	4-24	R. Kerler	4/23	3		X			X 4010	616210	5-6	5/5				Elect. Parameters
	1957	4-28	R. Kerler	4/28	4		X			N 410 C	616210	5-12	5/11				Plots, Elect. Parameters
J.K.	2016	5-26	R. Kerler	5/26	2		X			X 1140	616210	7-14	7/8				Electrical Parameters
	2034	6-16	P. Hanson	6/8	3		X			X 4010	616210	6-18	6/18		6/29	7/6	Electrical Parameters
	~~2035~~	~~6-16~~	~~P. Hanson~~	~~6/8~~	~~4~~		~~X~~			~~N 410 C~~	~~616210~~	Cancelled					~~Electrical Parameters~~
	2036	6-16	P. Hanson	6/8	29		X			2N696, 2N697	616210	6-23	6/22				Electrical Parameters
	2037	6-16	R. Kerler	6/11	94		X		W.E.	2N696, 2N697	616210	11-11		11/7			Vendor Comparison & Life
J.M.	2104	7-24	R. Kerler	7/28	19		X			2N1131	616210	8-7	8/7				Elect. Parameters, Plots
AP	2107	7-24	D. Ellings	7/28	27		X			2N696, 2N697 N410C, X4010	616210	8-6	8/5				Elect. Parameters
DJ	2199	10-2	Q.S. Hunter	10/2	335		X			S4035-V909167 2N697	616210	10-26	10/23				Receiving Inspection Units
JM	2246	10-21	R.A. Erickson	10/22	20		X			2N706	370491	1-8	11/25				Electrical Parameter
JM	2360	1-4	B. Bissonette	1/6	98		X			V909167	616210	1-18	1/15				Receiving Inspection
RG	2499	3-23	R.A. Erickson	3/21	12	X				FD 100	370491	3-30	3/30				Elect. Parameters
BNS	2589	4-21	R.A. Erickson	4/20	10		X			2N699	796130	6-13	6/13				Elect. Parameters
DO	2711	7-1	D.R. Miller	7/5	6		X			2N706	6823152	7-7	7/6				Elect. Par.
EC	2721+S	7-1	R.J. Kerler	7/6	20+10	X				FD 200 (V907618G)	616210	(20) 7-26 (10) 8-3	8/3				Elect. Par.
WN	2737	7-11	R.J. Kerler	7/11	5+5		X			2N1252 & 1253	616210	8-1	7/21				Elect. Par.
WC	2827	9-28	E.P. Deeb	9/27	390	X			Rheem T.I. - PSI	1N914	359834						Elect. Par.
EC	2828	10-25	E.P. Deeb	9/27	5+		X		TI - Sperry	2N706	359834	11-2	11/1				Elect. Par.
WC	2846	10-13	E.P. Deeb	10/13	25		X			2N1132	889221	10-24	10/21				Elect. Par.
RI	2915	12-6	R.A. Erickson	12/6	41		X		TI - Motorola PSI - Sperry	Various	9511104	12-12	12/12				Elect. Par.

FAIRCHILD I

ERA-1037

SEMICONDUCTOR TEST RECORD

FEDERAL

PAGE II

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	OTHER MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
46B				10	X			TP	IN58A-IN48A		1-7				1/7	Humidity & Temp Cyc.
(Formerly EF1069) 1090	1-4			4	X							4/9		4/10	4/10	" " "

FEDERAL

ERA-1037

SEMICONDUCTOR TEST RECORD

GAHAGAN

PAGE I

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST PARAMETER	TEST LIFE	SUMMARY	COMPLETE	REMARKS
29				62	X			Kemtron IR-TP	1N52 - 1N63 1N69 - 1N34A		6-25				6/25	Humidity & Temp cycling
347				12	X				1N143		3-8				3/8	Stability
1179	4-26			10	X				657			5/2		5/2	5/15	Against 900177
1217	7-9			10	X				1N34A			7/18		7/18	9/3	" 901563

Formerly EF1059

GAHAGAN

ERA-1037

SEMICONDUCTOR TEST RECORD GENERAL ELECTRIC

PAGE I

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST		SUMMARY	COMPLETE	REMARKS
												PARAMETER	LIFE			
29				6	X			Also Others	1N52		6/25				6/25	Humidity & Temp Cycling
45				6	X				4JA1B1		8/6				8/6	Life Test
46				21	X			Also Others	5 1N142 · 6 1N52 6 1N141 · 2 1N143 2 1N140		1/7				1/7	Humidity & Temp Cycling
85				10 ea	X			Others	1N39A · 1N67A 1N68A · G5S1		4/19				4/19	" "
91				1	X				4JA1B1		3/11				3/11	Vibration
107A				25	X	X		Others	6 1N67A · 6 2N43 4 2N43A · 6 2N78 3 ZJ11		11/15				11/15	Power Dissipation
173				25	X			Syl.	GT 847		4/2				4/2	Temp & Heat Dissipation
180				50		X			4JD1A31		1/9				1/9	Heat Storage · Reliability
204				1	X				4JA211CF1AA1		8/9				8/9	Evaluation
212				8	X			Syl	2N123		8/2				8/2	Power Dissipation
233				1		X		Other	4JD1A17		9/12				9/12	Temp.
253				14		X		GT	2N123		5/17				5/17	Parameter & Life
307				36		X			ZJ1-501		6/17				6/17	Hermetic Seal
435	7/11			20		X			2N123		9/27	9/27		9/27	9/27	Effect of Moisture-Fungus Proofing
830	8/12			2		X			2N123		8/19	8/12		8/26	8/26	Failed Component
856	8/25			60		X		Other	35 4JD1A70 25 2N396		7-20		6/5			High Temp storage (85°C)
860	8/25			1		X			2N123, FR#91		9/5	9/2		9/19	9/19	Failure analysis
878	8/29			103		X			ZJ11-501		10/2	9/9		10/8	10/8	Elec. Parameter
932	9/26			3		X			3-10 & 35		9/29	9/26		10/17	10/17	Unijunction silicon
948	10/2			25	X				4JA60A		12-23	10/23		12/23	12/23	Plots
986	10/21			10		X			4JD1A70		4-19	10/31		11/24	11/24	Initial data

GENERAL ELECTRIC

ERA-1037

SEMICONDUCTOR TEST RECORD GENERAL Instrument

	PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	Other MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
J.K.	1819		HN Frazier	3-19	20	x				IN540	359281	10/5		6/3	7/15	7/20	1000 hr. life test
J.K.	1820		HN. Frazier	3-19	15	X				IN540	359281	10/5		6/3	7/15	7/20	" " " "
J.K.	1828		H.N. Frazier	3-19	20	x				IN540	359281	10/5		10/5			Evaluation
EC	2765	8-12	R.M. Englund	8/15	25	X				IN1202	659170	10-25	8/23				Elect. Par.
RI	2944	12-20	R.A. Erickson	12/20	25+50	X				555 - 570	796710	2-24	2/24				Envir.
RI	3037	2-21	D.E. Zander	2/21	6		X			V910520	793120	3-2	3/2				Elect. Par.
JK	3134	4-12	R.J. Kerler	4/12	25		X			GTM 2112	9511104	4-26	4/24				Elect. Par.
JK	3195	5-24	D.E. ZANDER	5/24	100	X			CLEVITE	R 275	698225	6-30	6/29				ELECT. PAR. & ENVIR.
RR	3242	6-23	D.E. ZANDER	6/23	10	X				IN 1202	698225			2/20	2		LIFE

G I

ERA-1037

SEMICONDUCTOR TEST RECORD GENERAL TRANSISTOR

PAGE I

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	Other MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST PARAMETER	TEST LIFE	SUMMARY	COMPLETE	REMARKS
107A				7		X		Also Others	GT 122		11/15				11/15	Power Dissipation
224				35		X		SYL	14 UKC 903 210FC 905		2/25				2/25	Operational Life
253				30		X		GE	17GT122A 4GT760 9GT762		5/17				5/17	Param + Life
364				20		X			2N316		4/19				4/19	Parameters
368				20		X			2N316		5/17				5/17	Temp Storage
402	6/11			40		X			903207B		9/27	9/27	9/27	9/27	9/27	Voltage Breakdown
434	7/11			20		X			GT34HV		9/13	9/13		9/13	9/13	Effect of Moisture-fungus-proofing
573	2/6			100	X				111318		2/19	2/19		2/19	2/19	Mechanical Shock
661	6/26			20		X			V904217A V904219B		7/30	7/7		7/8	8/1	Switching Time · Fwd Gain
805	7/31			25		X			GT 123		8/26	7/31		8/12	8/12	Hermetic Seal
807	8/4			50		X			904218B		8/19	8/12		10/17	10/17	Parameter Distribution
808	8/4			1		X			904218B		8/19	8/12		8/19	8/19	Breadboard Ckt Failure
819	8/11			25		X			GT 1147		10/30	9/5		10/24	10/24	Vendor Comparison
829	8/11			3		X			2N604		8/25	8/22		9/23	9/23	To Justify further Evaluation
845	8/18			22		X			GT2N317		8/25	8/20		9/19	9/19	Parameter Distribution Special Test Circuits
852	8/18			100		X			2N604		8/25	8/23		9/19	9/19	Component Evaluation
855	8/26			35		X			4JD1A70		9/9	9/9		9/29	9/29	Hermetic Seal
856	8/25			25		X		Also Others	2N123		7/20		6/5			High Temp. Storage (85°C)
858 AB CD E	8/22			180		X		Ray Syl	V903214 · V903210 V902226 · V903213 V903212		11/11	9/26		11/18	12/5	Failure Analysis
918	9/19			1		X			GT 816		10/20	10/14		10/20	10/20	" "
921	9/19			1		X			2N604		10/6	10/2		10/7	10/7	" "
966	10/15			147	X				7 V TYPES		6/13/61	11/30		8/15	10/2	Shock Test
976	10/14			2		X			904218B		10/20	10/16		11/5	11/5	Failure Analysis
985	10/21			5		X			2N604		11/4	11/3		12/3	12/3	" "
996	10/23			24		X		Ray	V903210		7-10	11/4		12/10	12/10	" "
997	10/23			25		X		Syl.	V903214		7-10	11/19		12/16	12/16	" "

GENERAL TRANSISTOR

ERA-1037

SEMICONDUCTOR TEST RECORD

HOFFMAN

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
575	2/11			5	X				1N205		2-19	2/19		2/19	2/19	Zener diode char.
683	7-14			35	X			5each	1N465-66-67-68-69-70		8-19	8/7		9/22	9/22	" " "
963	10-9			50	X				1N430		2/4 47	10/30		12/11	12/11	Dynamic Impedance
1026				6	X				1N138A							
1027	10-26			6	X				1N431							For use only - not test
1324				6	X				D11082			12/23		1/3	1/6	Capability (V902818B)
1392				20	X				902254			3/26		6/11	6/18	" (V902254)
1410				25	X				902818			4/10	/	4/17	4/21	Life test at 150°C
1495	10-30	RH Ness	10/30	25	X				1N467	359281	2-4	11/9		12/19	12/19	Zener diodes
1594	12-3	K. Hoglund	12/2	12	X				1N702	616210	12-18	12/18		1/14	1/14	R&I
1661	1-12	C.Christensen	1/12	19	X				1N214 & 102857A	227231	2-5	2/4		2/10	2/10	Plot
1806	3-11	K. Hoglund	3/11	6	X				1N1316	616210	3-27	3/17		4/1	4/7	R&I
1808-S	4-21	K. Hoglund	4/21	30	X			U.S. Sem Transitron	1N465-470	616210	5-19		1/9			Vendor Comparison
1937	4-24	K. Hoglund	4/23	623	X			Tran, PSI, U.S. Sem, Auto, IRC, WE	1N1769	616210	5-31(49) 3-30(40)	3/27	5/2	3/30	4/3	Vendor Comparison

Formerly EF1059

JK

HOFFMAN

ERA-1037

SEMICONDUCTOR TEST RECORD

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST PARAMETER	TEST LIFE	SUMMARY	COMPLETE	REMARKS
29				6	X			Also 9 Other Mfgr	1N68A		6/25				6/25	Humidity & Temp Cycling
33				6	X			Also Others	1N68		10/26				10/26	" " "
46				22	X			Also Others	6 HD2126-6BS1031 6 1N67A-4 1N68A		1/7				1/7	" " "
85				10ea	X			Also others	HD2126-HD2705-HD2706		4/19				4/19	" " "
97				65	X			Also others	50 HD2126 15 HD2139		6/30				6/30	" " "
100				20	X			Also Others	HD2152		6/30				6/30	" " "
101				5	X			Trans	HD2165		3/12				3/12	Operational
107A				16	X			Others	6 1N67A 6 1N96 4 HD2126		11/15				11/15	Power Dissipation
126A				26	X			Trans	1N118		2/2				2/2	Reliability & Temp.
137				110	X				1N118		1/15				1/15	Temp.
139				50	X				1N118		12/14				12/14	Temp & Humidity Cycle
166				20	X			Others	HD2126		3/12				3/12	Comparison
168				89	X				1N118		12/14				12/14	Diode Seal
206				25	X			others	HD2197		8/2				8/2	Reliability
270				6	X				SA2		11/2				11/2	Characteristics
347				6	X			Other	HD6752		3/8				3/8	Stability Char.
361				1400	X				23475 83135		8/21				8/21	Requirements DS 1004A
369				320	X			Trans	1N118		9/4				9/4	Comparison
378				50	X			TRANS	1N118		6/26				6/26	Vibration
386				50	X			Others	HD2193		10/11				10/11	Shelf Life
431	7/10			100	X				HD2126		8/13	8/13		8/13	8/13	Leakage Current
470	8/24			90	X				GA4-1		9/28	9/28	9/28	9/28	9/28	Vibration Shock Soldering
523	12/2			100	X			Other	RRU 111318		—	8/7	8/7	8/11	8/11	Vibration Life
524				75	X			other	HD6589		—	1/16		8/15	8/15	Vendor Screening
527				75	X			other	HD2183		—	1/14		8/11	8/11	" "
528	12/6			20	X			Other	HD2126		3-16		3/9			" "

ERA-1037

SEMICONDUCTOR TEST RECORD

IRC

PAGE I

	PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	OTHER MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST PARAMETER	TEST LIFE	SUMMARY	COMPLETE	REMARKS
	29				15	X			Canagan Komsron TP	1N52 1N63 1N69 1N34A		6-25				6/25	Humidity & Temp-cycling
	46				17	X			TP	1N63-C44-G14		1-7				1/7	" " "
	1556	11-7	RH Ness	11/10	25	x				MZ3.9A	359272	2-4	11/12		12/9	12/9	Elec. para. & Hermetic seal
	~~1593~~	~~12-3~~	~~KM Hoglund~~	~~12/2~~	~~12~~	~~X~~			cancelled	~~25H20~~	~~616210~~	cancelled				2-23-59	~~R&I~~
	1677	1-20	HN Frazier	1/20	25	x				45L30	359281	To 1846 3-23	2/4		2/10	2/16	Elec. para.
GG	1837	3-19	KM Hoglund	3-19	36	x			GE-West.	25H20	616210	3-30	3/29		3/30	4/3	Plots
JK	1846	3-23	HN Frazier	3-23	75	x			GE-West.	45I30	359281	10/5		9/29			1000 hr life test
JK	1853	3-27	RH Ness	3-25	25	x			Auto	MZ3.9	359281	7-13		7/10			Operating life test
J.K.	1937	4-24	K. Hoglund	4/23	623	X			Tran, Hoff, DSI, U.S.Sem, Auto, W.E.	SV808, 1N1769, 1N1522	616210	5-31		5/2			Vendor Comparison
JK	2009	5-22	K. Hoglund	5/22	36	X			G.E. Westinghouse	25H20	616210	3-15		3/3			Vendor Comparison
JK	2019	5-28	K. Hoglund	5/28	10	X				1N1509	616210	6-16	6/12		6/12	6/30	R&I
J.K.	2075	7-6	K. Hoglund	7/6	60	X			Motorola	1N1608	616210	9-6		2/29			Life Test, Vendor Comp.
	2100	7-20	K. Hoglund	7/22	50	X				69-0761	616210	2-26		2/19			Reverse Characteristics, Life
	2113	8-3	K. Hoglund	7/31	60	X			Transitron	1N1601	616210	2-1-61		12/12	0		Life Test, Vendor Comp.
GC	2200	11-18(50) 10-5(6)	12-7(49) R. Kerler	10/2	105	X				V907209	616210	(49) 12-16 (50) 11-25 (6) 10-12	12-15 11-24 10-12				Inspection Engineering
GC	2347	12-23	Bissonette	12/29	30	X				V907209	7342152 616210	1-11	1/11				R&I
GC	2350	12-22	Bissonette	12/29	30	X				V907209	7302152 616210	1-5	1/4				Evaluation
GC	2384	1-21	Bissonette	1/21	6	X				V907209	616210	1-23	1/23				Component Evaluation
GC	2442	2-22	Bissonette	2/22	3	X				V907209	7342152 616210	3-15	3/14				Component Evaluation
BNS	2575	4-11	R.J. Kerler	4/13	45	X				66-2808 (V907209C)	616210			2/26	2		Life
EC	2774	8-23	R.M. Englund	8/19	25	X				1N1202	659170	10-25	8/24				Elect. Par.
WC	2868	10-28	D.R. Anderson	10/28	24	X				907209	90982	11-9	11/1				Elect. Par.
JK	3035	2-20	D.R. Anderson	2/20	42	X				9740295	92721,2,3	2-27	2/26				Elect. Par.

IRC

ERA-1037

SEMICONDUCTOR TEST RECORD

Motorola PAGE I

	PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	OTHER MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
	973	10-14			2		X			2N595		10-22	10/22		11/4	11/4	Prelim. test.
Formerly EF105?	1314				20		X			2N311			12/18		1/2	1/6	Capability
	1592	12-3	KM Hoglund	12/2	10		X			2N618	616210	12-30	12/29		1/16	1/16	R&I
	1734	2-6	RJ Kerler	2/6	200		X			2X559	616210	4-28	3/5		5/8	5/12	Reliability
	1740	2-10	KM Hoglund	2/10	6	X				1N1566	616210	2-19	2/19		2/23	3/3	Initial data
GG	1799	3-10	RH Ness	3/11	1		X			MN86E	359281	4-7	3-27		3-30	4/6	Plot - HST
GG	1803	3-11	KM Hoglund	3/11	6		X			2N376	616210	6-23	6/23		6/1	6/8	R&I
JK	1851	3-26	KM Hoglund	3-25	10	X				50M10Z	616210	4-9	4/8		4/22	4/22	R&I
JK	1852	3-26	KM Hoglund	3-25	4	X				50M3025	616210	4-9	4/8		4/21	4/27	R&I
GG	1859	3-30	KM Hoglund	3-27	60	X			Trans-GE West-Auto	1N1570 1N538 - 1N1220	616210	6-27		6/9	(60)		Vendor Comparison
GG	1860	3-30	KM Hoglund	3-27	60	X			Trans-GE West-Auto	1N1570 1N538 - 1N1220	616210	(5) 7-10 6-3	5/25		7/10	7/16	" "
GG	1872	4-6	KM Hoglund	4-3	50	X			GE-Auto Trans-West	1N1570	616210	(20) 5-14 (28) 6-27		6/9	(60)		" "
JK	1919	4-20	K Hoglund	4/16	8	X				50M10Z	616210	8-1		7/26			Point Measurements
	1948	4-28	R. Kerler	4/28	200		X			2X559	616210	(185) 9-11 (5) 9-18 (10) 4-13	/	9/18			Life test, Vendor. comp
	1964	5-4	K. Hoglund	5/1	8	X				50M17ZR5	616210	5-18	5/7		6/2	6/8	R&I
J.K.	2070	6-30	K. Hoglund	6/29	60	X				50M30ZR5 50M17ZR5	616210	1-3		1/3	\		Storage & Power (Life)
J.K.	2075	7-6	K Hoglund	7/6	60	X			IRC	10M24Z	616210	9-6		2/29			Life Test, Vendor Comp.
ACT	~~2230~~	~~10-16~~	~~Lee Ruetz~~	10/13	~~100~~		X			Ser. No. 000-099 ~~2N695~~	~~800202~~	Cancelled 11-11-59					~~Receiving Inspection~~
JM	2234	10-16	R.J. Kerler	10/16	200		X			SD84	616210			2/15	\		Life
GC	2265	11-2	B. Bissonette	11/3	23	X				V907621	616210	11-16	11/13				Component Evaluation
GC	2269	11-2	B. Bissonette	11/3	34	X				V907350	616210	11-12	11/12				Component Evaluation
GC	2368	1-8	B. Bissonette	1/15	19	X				V907621	7342152 616210	1-13	1/13				Component Evaluation
G.C.	2379	1-15	B. Bissonette	1/19	25	X				V907621	7342152 616210	2-1	1/30				Component Evaluation
G.C.	2388	1-22	B. Bissonette	1/22	~~30~~ 60	X				V907350B	616210	(30) 2-9 (30) 2-5	2/8 2/4				Component Evaluation
BNS	2409	2-1	R.P. Fischer	2/2	100		X			5M-15	[illegible]	2-12	2/4				Parameters
BNS	2425	2-12	R.P. Fischer	2/12	100		X			5M-15	659170	(61) 5-3 (39) 2-29		4/28			Life Test

MOTOROLA I

ERA-1037

SEMICONDUCTOR TEST RECORD

OHMITE

PAGE I

	PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	other MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
	790	7-23			80	X						7-21	7/21		9/29	9/30	H. S. T.
Formerly EF 1059	1405				20	X				118			3/20		4/25	4/25	Diode, High }
	1406				20	X				113			3/26		4/25	4/25	conduction source }
	1470				11	X				113					6/4	6/9	Correlation
GG	1809	3-17	A.A.Kaine	3/16	59	X				OMC 232-270-720	613120	6-18	4/17		5/8	5/12	Plots. HST
RI	3021	2-13	B.N. Svendsen	2/13	50 of 150	X			Clevite-G.T.	V 908202 F	846140	4-13	3/31				Shock

OHMITE

ERA-1037

SEMICONDUCTOR TEST RECORD Pacific Semiconductor PAGE I

	PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	Other MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST PARAMETER	TEST LIFE	SUMMARY	COMPLETE	REMARKS
	467	8-26			130	X				GD 2030		9-26	9/26	9/26	9/26	9/26	Vibration-shock-soldering
	523	12-2			100	X				1N318		—	8/7	8/7	8/11	8/11	" -Life
	671	7-7			20	X				GD 2056		4-19	7/24		7/31	7/31	Parameter distribution
	806	7-31			15	X				GD 2056		8-26	8/7		8/14	8/14	Effect of dip soldering
	818	9-5			15	X				PS 420		—	1/16		9/16	9/16	Surge current
	833	8-12			15	X				PS 420		8-12	8/12		9/22	9/22	Component-evaluation
	873	8-28			30	X				1N643		9-29	9/19		9/22	9/22	Design info
	933	9-26			50	X				1N663		10-14	10/8		10/23	10/23	R&I
Formerly EF1059	1271	9-18			10	X				GD 2030			9/27		10/29	10/30	Capability DS 1004
	1639	12-18	KM Hoglund	12/18	20	X				PS 6466-10 PS 6466-10	616210	1-12	1/5		1/23	1/23	Elec. para.
J.K.	1876	4-6	PJ Pearsall	9-3	103	X			Rdy-T I Sperry Trans, H&S, US Semi, Auto, IRC, WE	1N645	359272	9-29		8/10			Capabilities DS 1078
J.K.	1937	4-24	K. Hoglund	4/23	623	X				1N1769, PS 6313's	616210	5-31		5/2			Vendor Comparison
J.K.	1960	4-28	P. Pearsall	4/29	30	X				1N645	359272	7-31		7/24			Elec. Parameters, Life test
GG.	1971	5-4	R. Kerler	5/1	10	X				1N661	616210	5-22	5/21		5/27	6/3	Elect. Parameters
JM	2076	7-6	R. Kerler	7/6	13	X				1N691	616210	1-13	7/10				Elect. Parameters, Plots
	2172	9-10	E. Deeb	9/10	9	X				XD-00's	9535104	9-18	9/18				Elect. Parameters, Plots
GC	2201	10-5	K.M. Hoglund	10/2	50	X				PS-6714	616210	11-3	10/16				Receiving Inspection
	2270	11-2	B. Bissonette	11/3	57	X				V909073	616210	11-18	11/16				Component Evaluation
GC	2282	11-16	R. Kerler		6	X				1N723A	616210	11-18	11/17				Parameter
GC	2322	12-4	R. Kerler	12/3	2		X			2N697	616210	12-29	12/28				Electrical Parameters
HS	2422	2-10	R. Kerler	2/12	6		X			2N1409	616210	3-4	3/3				Parameters
BNS	2530	3-29	R.J. Kerler	3/29	25		X			V909167A (PT805)	616210	(15) 4-15 (10) 5-19	5/16				Elect. Parameters, Shock
BNS	2532	open	J. Brinda	3/30	120	X				V909073 B (1N466)	6823152 616210	5-31	5/27			✓	Elect. Parameters
BNS	2576	4-11	R.J. Kerler	4/13	48	X				PS 6714	616210	3-17		12/13	0		Life
BNS	2582	open	J. Brinda	4/15	15	X				SV1137	616210	4-22	4/21				Elect. Parameters
BNS	2595	4-21	R.A. Erickson	4/20	10		X			2N1409	796130	6-13	6/13				Elect. Parameters

PACIFIC SEMICONDUCTOR I

ERA-1037

SEMICONDUCTOR TEST RECORD

PHILCO

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	Other MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
233				1		X		SYl-GE	SB100		9/12				9/12	Temperature
519	11/20			50		X		Sprague	111350		6/10	6/10	6/10	6/10	6/10	High Temp Storage
534	12/17			24		X		Hughes Sprague	111350		—	1/15		1/15	1/15	Dip-Solder
535	12/17			36		X		Sprague	S3001		2/28	7/28	7/28	7/28	7/28	Lead fatigue, Shock
540	12/23			300		X			T 1166		1/27	1/27		1/27	1/27	Elect. Parm
544	1/2			50		X		Sprague	111350		5-13-9		3/18	5/4	5/8	5000-hr Storage 71°C Life
568	1/28			200		X			111350 S3001 -T1002		2/14	2/14		2/14	2/14	Correlation Data
644	6/19			180		X			2N501		3-29	6/19	12/15/59	/	/	High Temp Storage
645	6/19			30		X			2N501		6/30	6/16		6/17	6/17	Parameter Distribution
653	6/26			85		X			MICRO-ALLOY 2N393 (T1166)		4-19	6/26	4/7	2/18	2/18	Storage at 85°C
675	7/14			43		X			T1070		4-19	7/16		7/19	7/19	Hermetic Seal
680	7/9			25		X		Sprague	111350		4-19	7/9	2/20			Storage at 84°C
682	7/14			700		X			2N501		8/28	7/14		9/23	9/23	Parameter Distribution
699	7/23			1		X			2N501		8/19	8/7		8/21	8/21	Ringing in O.P. waveform
787	7/23			40		X			2N501		8/15	8/8		9/18	9/18	Circuit (Breadboard) Failures
800	7/29			18		X			2N501		8/19	8/8		9/8	9/8	Breadboard Ckt. Failures
840	8/13			25		X			2N501		8/22	8/20		9/19	9/22	Failures Analysis
850	8/18			29		X			2N501		9/5	8/28		9/16	9/19	" "
855	8/26			25		X		ALSO Others	L5044A		9/9	9/9		9/29	9/29	Hermetic Seal
856	8/25			25		X		ALSO Others	L5044A		7/20		6/5			High Temp Storage (85°C)
863	8/25			17		X			2N501		9/5	9/3		9/19	9/19	Failure Analysis
869	8/25			200		X			2N501		9/29	9/23		9/24	10/2	Marg Units-Circuit Design 9/17
870	9/11			25		X			2N501		9/30	9/30		1/21	1/21	Design Info
874	8/29			17		X			2N501		9/19	9/15		9/23	9/23	Failure Analysis
885	9/11			25		X			2N501		9/24	9/24		10/8	10/8	Det. Bulk Res Op Pt.
~~886~~	~~9/4~~			~~25~~	~~X~~			~~T.I. RAY.~~	~~1N645~~		~~9/19~~	~~9/11~~		~~9/23~~	~~9/23~~	~~Init. Data~~

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PHILCO I

ERA-1037

SEMICONDUCTOR TEST RECORD

PHILCO PAGE II

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST PARAMETER	TEST LIFE	SUMMARY	COMPLETE	REMARKS
892	9/8			13		X			2N501		9/29	9/25		10/2	10/2	Failure Analysis
906	9/16			7		X			2N501		9/29	9/25		10/2	10/2	" "
917	9/19			45		X			2N501		3-9 6-16	10/16		6/5	6/16	m/c (Tab Effect)
920	9/19			12		X			2N501		10/6	10/2		10/6	10/6	Failure Analysis
922	9/19			3500		X			2N501		1-15	1/15		2/17		Rec. Insp
942	9/30			10		X			2N601		11/18	11/17				" "
943	9/30			?		X			2N501		A-2, AA, AO, AC [illegible]	4/24				Failure Analysis - Rev.
984	10/21			100		X			2N501		3/29		1/6			Correl - Init. Leak & Hyst & Life
1022	8/29			2		X			2N207							
1023	8/29			2		X			L5122							
1024	8/29			2		X			L5130							
1058	11/29			5		X			L5134			12/10		12/20	12/20	Units returned to C.P. 12-20
1072				60		X			T1164			12/13	12/13	6/11	6/11	Too expensive 10 for $350[illegible]
1084	—	Cancelled	—	—		X		—	T1025	Cancelled	—	—	—	—	/	Too expensive 10 for $350.
1085	12/21			65		X			T1164			1/4		3/7	3/7	
1086				115		X			T1164			1/4		1/5	1/5	
1087				248		X			T1164			1/4	2/13	1/5	1/5	
1091	1/5			10		X			T1070			2/20		3/7	3/7	Mil Version of T1164
1121				10		X			T1164			2/6		3/7	3/7	Special test for CAJ
1126	2/26			4		X			T1041			5/2		5/2	5/15	
1135	3/19			4		X			T1164			3/19		3/19	3/20	
1146	4/8			50		X			T1073			4/10		4/10	4/17	
1147	4/12			40		X		GE	T1164			4/15		4/23	5/20	Test for B. Boylan
1178	4/25			5		X			L5409			4/25		5/1	5/1	
1185	5/10			65		X			V902908				5/20			
1215	7/9			20		X		GT	T1164			7/23		8/2	8/22	Hermetic seal - Life test

Formerly EF 1059

PHILCO II

ERA-1037

SEMICONDUCTOR TEST RECORD

PHILCO

	PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	Other MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST PARAMETER	TEST LIFE	SUMMARY	COMPLETE	REMARKS
JK	3412	10-16	G.L. KRAKE	10/16	3		X		1	2N769	796110	11-1-61	10/30				h_{ie}, h_{oe}, α, vs FREQ.
MB	3477	12-12	D.A. OINES	12/12	10		X			T2396 (909974)	946211						BV_{CEO}
RI	3505	1-8	K.B. Dalager	1/8	10 10		X		MOT.	2N1495 (909974)	149501						K's & switching
RG	3537	2-6	K.B. Dalager	2/6	2		X			2N1495 (909974)	998160	3-23	2/22				Thermal Resistance

ERA-1037

SEMICONDUCTOR TEST RECORD

RCA PAGE I

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
11				4	X				TA161B		2/29				2/29	Comparison
691	7/8			10		X			TA1725		7/30	7/31		8/26	8/26	Parameter Distribution
696	7/23			50		X			2N398		7/30	7/24		7/24	7/25	Indicator Light Circuit Suitability
698	7/23			12		X			TA1798		8/19	8/13				Parameter Distribution
809	8/4			10		X			2N580		8/19	8/12		9/19	9/19	" "
855	8/26			25		X		Also Other Mfgr	TA1726A		9/9			9/29	9/29	Hermetic Seal
856	8/25			25		X		" "	TA1726A		7/20		6/5			High Temp Storage (85°C)
861	8/25			12		X			2N270		9/5	9/3		9/23	9/23	Parameter Distribution
888	9/8			3		X			TA1796		11-11	9/23		9/29	9/29	Preliminary Data
893	9/8			10		X			2N247		9/19	9/15		9/30	9/30	Data For Circ. Design
1013	6/25			6		X			TA1576					6/14	6/14	Data lost til 6·14·57
1019	7/26			4		X			TA1575			8/17		6/5	6/5	" " " 6·5·57
1020	7/26			1		X			TAE1579					6/14	6/14	" " " 6·14·57
1021	7/26			4		X			TA1587							
1029	10/24			3		X			TA1621			1/4		2/12	2/12	
1030	10/24			5		X			2N267			2/12		3/12	3/12	
1032	11/20			6		X			TA1621A							Hardenberg has these
1033	11/20			6		X			TAE1630							" " "
1034	11/20			6		X			2N269			11/28		12/18	12/18	
1035	11/20			2		X			TA1605			12/9		12/17	12/17	
1047	11/14			6		X			TA1586			12/13		12/26	12/26	
1048	2/5			100		X			2N270				2/5			Reg # 11189
1049	1/17			26		X			TA1586			1/23		3/5	3/5	Units to R. Lorenze 4/15
1071				6		X			TA135			3/12		3/12	3/12	
1111	2/8			64		X			TA1586			1/23	2/25	11/25	11/25	Part of Order on 49
1112	2/8			65		X			2N269			3/3	3/11	9/12	9/12	Failed units sent to RCA for failure analysis

Formerly EF 1059

RCA I

ERA-1037

SEMICONDUCTOR TEST RECORD RADIO RECEPTOR

PAGE I

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST PARAMETER	TEST LIFE	SUMMARY	COMPLETE	REMARKS
29				6	X			Also 9 Other Mfgr.	1N52		6/25				6/25	Humidity & Temp Cycling
46				13	X			Also Others	3DR63-6DR31-41N64A		1/7				1/7	" " "
107A				6		X		Also Others	RR 122		11/15				11/15	Power Dissipation
155				7ea.	X			Others	DR310 DR311		5-8				5/8	
206				12	X			Others	DR 294		8/2				8/2	Reliability
277				28	X			Trans	DR299		1/15				1/15	Humidity & Temp Cycling
347				8ea.	X			Other	DR369 DR370		3/8				3/8	Stability Char.
527				75	X			Also Others	DR 291		—	1/14		8/11	8/11	Vendor Screening
528	12/6			20	X			Also Others	DR292		3/16		3/9			" "
531	12/6			25	X			Also Others	DR291		9-10	1/10		8/15	8/15	Temperature Storage
857[c]	8/22			7	X			Also Others	V900172		11/11	9/22				Failure Analysis
867	8/28			20	X				1N658		9/11	9/10		9/25	9/25	Capability Eval.
994	10/23			7	X			Also Others	V900171		7-10	11/11				F. A.
1078				25	X				DR299			2/21		2/21	5/21	
1125	2/25			10	X				DR292			2/26		4/29	5/22	
1136	3/26			6	X				902818			5/15		5/15	6/19	
1164	4/18			12	X				DR 291			6/7		6/7	6/19	
1165	4/18			12	X				DR 292			5/1		5/1	6/11	
1166	4/18			12	X				DR293			6/11		6/11	6/19	
1167	4/18			12	X				DR294			5/1		5/1	6/11	
1168	4/18			12	X				DR295			5/1		5/1	6/19	
1169	4/18			12	X				DR299			4/19		4/25	5/24	
1170	4/18			12	X				DR355			5/2		5/2	5/16	
1171	4/18			12	X				1N67A			8/27		9/17	9/18	
1191	6/3			6	X				DR403			6/18		6/18	6/19	
1246	8/26			12	X				DR385			8/27		9/26	9/27	Capability Test

Formerly EF1059

RADIO RECEPTOR

ERA-1037

SEMICONDUCTOR TEST RECORD

RAYTHEON

PAGE I

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
29				6	X			Also 9 Other Mfgr.	CK707		6/25				6/25	Humidity & Temp Cycling
33				6	X			Also Others	1N67		10/26				10/26	" " "
46				6ea.	X			Also Others	1N67 1N58A		1/7				1/7	" " "
46B				6ea.	X			Also Others	CK708 - CK747		1/7				1/7	" " "
100				20	X			Also Others	CK835		6/30				6/30	" " "
105				2	X				CK776		10/27				10/27	Oper. Characteristics
107A				15		X		ALSO OTHERS	CK750 · CK760 CK761 · CK762		11/15				11/15	Power Dissipation
182				20		X			2N113 · 2N114		1/2				1/2	Heat Storage Ability
294				100		X			2N112 · 2N113		7/29				7/29	Comparison
310				10	X	X			CK777		1/23				1/23	Evaluation
389	4/26			50		X			CK760		9/20	9/20	9/20	9/20	9/20	Voltage Breakdown
684	7/14			5		X			2N329A		8/25	8/22		9/22	9/22	Parameter Distribution
687	7/17			12		X			V904217A		7/30	7/17		9/25	9/25	Switching Time · Fwd Gain
818	9/5			15	X			Also Others	1N697		—	1/16		2/16	2/16	Surge Current
834	8/12			15	X				1N645		8/18	8/12		9/22	9/22	Component Evaluation
858E	8/22			44		X		GT SYL	V903210		11/11	9/26		11/18	12/5	Failure Analysis
865	8/28			6		X			QC148		9/11	9/8		9/30	10/1	Lab · Samples · Eval
866	8/28			6		X			QC153		9/11	9/8		9/26	9/26	Lab · Samples · Eval
886	9/4			25	X			T. I. Philco	1N645		9/19	9/11		9/23	9/23	Init. Data
896	9/8			10		X			2N661		10/6	10/1		10/22	10/22	" "
940	9/30			100		X			904217B		10/14	10/10		11/4	11/4	Rec. Insp.
956	10/6			14	X				1N165		—	10/29		11/5	11/5	Mech. Str.
996	10/23			17		X		GT	V903210		7-10	11/4		12/10	12/10	Failure Analysis
1097	1/7			10		X			2N114			2/4		2/6	3/5	Round Robin
1100	1/4			38		X			2N113			2/6		2/8	2/9	From Doug Larson
1101	1/4			38		X			2N114			2/6		2/8	2/9	Checks new specs Raytheon

Formerly EF1059

RAYTHEON I

ERA-1037

SEMICONDUCTOR TEST RECORD

RAYTHEON PAGE II

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	OTHER MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
1108	1/15			3		X			UFC759			1/15		2/4	3/5	Units to C.A.J. 2-21-57
1109	1/16			3		X			UFC760			1/15		2/4	3/5	" " " 2-21-57
1137	3/27			18		X			903209			3/28		4/23	4/30	
1138	3/27			18		X			903210			3/29		4/23	5/22	
1139	3/27	3 units to YMB		18		X			903211			3/29		4/23	5/23	3 units to YMB
1141	4/1			10		X			2N114			4/3		4/3	4/3	Round RoBin II
1175	4/22			10		X			2N114			4/24		4/24	4/26	" " "
1214	7/8			2	X			Trans Hughes	CK840			7/10		7/10	7/26	Return to R Boylan Capability test
1216	7/5			10		X		Philco	2N114			7/5		7/5	7/8	Round robin
1255	9/6			100		X			903211A			10/31				Determine uniformity
1256	9/9			100		X			903209A			3/7				" "
1258	9/9			100		X			903210			11/1				" "
1260	9/12			50		X			903209A			9/27		10/24	10/25	Proposed spec change
1318				100		X			904276A			2/26		6/16	6/25	Capability & Life P_z vs T_j
1338				12		X			QC 171			1/20		3/12	2/13	" 500hr. stor. (902226A)
1349				100		X			903210A			[illegible]	/			Life test
1355				10		X			QC172			2/26		3/18	3/20	Capability & 500hr storage
1378		1 unit to VMB		6		X			903778			7/28		4/16	4/21	" (903778)
1380				6		X			2N427			4/2		6/9	6/13	" test
1415				6		X			ES			4/1		4/23	9/12	" "(9001518)
1456				12		X			902226B			8/4		8/13	8/20	" (Y902226B)
1466		Units to R.England		10		X			CK64			7/14		8/14	8/14	" (DS 1081B)
1572	11-19	CA Johnson	11/19	36		X			QC174	613120	3-5	2/18		3/17	3/29	Elec.para. & Hermetic seal
1578	11-24	CA Johnson	11/21	100		X			V902226B	613120	3-20	3/18		5/20	5/25	" " 70°c stor. Hermetic Seal
JK 1801	3-11	P.G. Haxsen	3/11	13		X		RCA WE GT	2N661	616210	3-27	3/27		3/30	4/7	F.A.
J.K. 1876	4-6	PJ Pearsall	4-3	103	X			PSI-TI Sperry	1N645	359272	9-29		8/10			Capabilities DS 1078

Formerly EF 1059

Raytheon II

ERA-1037

SEMICONDUCTOR TEST RECORD

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PAGE I

	PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	Other MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST PARAMETER	TEST LIFE	SUMMARY	COMPLETE	REMARKS
GC	2332	12-11	R.J. Kerler	12/15	2	X				2N697	616210	12-29	12/29				Elect. Par.
AL	2648	5-11	R.J. Kerler	5/11	5		X			RT 5019	616210	6-8	6/1				Elect. Par.
AL	2693	6-10	R.J. Kerler	6/9	2		X			RT 5004	616210	6-15	6/15				Elect. Par.
EC	2718	7-5	R.M. Englund	7/5	19	X				V907806 (AE 1054)	659170	8-10	8/10				Elect. Par.
LB	2724	7-1	P.J. Pearsall	7/6	10+10		X		Trans.	V905609 (RT5044)	243146	8-10	8/10				Elect. Par. + Envir.
LB	2725	7-1	R.J. Kerler	7/6	9	X				V907618G	616210	8-15	8/15				Elect. Par.
DO	2800	9-8	K.B. Dalager	9/9	300	X				Rd 2196	818140	9-20	9/19				Elect. Par.
WC	2827	9-28	E.P. Deeb	9/27	390	X			Fairchild T.I. - PSI	1N914	359834						Elect. Par.
EC	2833	10-3	R.J. Kerler	9/29	25		X			V909167C (RT5019)	841531			/			Life
WN	2860	10-26	E.P. Deeb	10/24	27		X			2N1252	889241	11-21	11/1				Elect. Par.
WC	2891	11-15	E.P. Deeb	11/16	25		X			2N718	889241	11-28	11/22				Elect. Par.
RI	2911	12-1	E.P. Deeb	12/1	100	X				RD2196 (V908861)	889233	1-16	1/10				Elect. Par.
RR	2917	12-7	D.A. Oines	12/7	5	X				RD 921	841531	1-24		1/10			Life
HZ	3046	2-28	E.P. Deeb	2/28	100	X				1N905	889233	3-13	3/9				Elect. Par.
JK	3055	3-2	D.A. Oines	3/2	6 of 19		X		T.I.	2N718A	9511104	3-9	3/8				Elect. Par.
JK	3065	3-7	P.J. Pearsall	3/7	5		X		Fairchild	2N657	9431104	3-13	3/3				Elect. Par.
JK	3130	4-6	P.J. Pearsall	4/10	18		X			V909876	521333	4-21	4/21				Envir.
MB	3145	4-19	D.E. Zander	4/19	27	X				1N691	699234	4-27	4/26				Shock
JK	3353	9-13	E.P. DEEB	9/13	200	X				RD2241 (907823)	779293	11-3-61	11/1				ENVIR. & LIFE.
MB	3368	9-22	R.J. KERLER	9/22	4	X				CSR210-319A (907602)	149501						LIFE
MB	3460	11-29	R.J. HACKEL	11/28	100		X			RT 5044	146241	12-8	12/8				hFE @ 25°c & -65°C

ERA-1037

SEMICONDUCTOR TEST RECORD

SEMCOR

PAGE I

	PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	OTHER MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
Formerly EF1059	1321				20	X				Z-120			11/13		12/18	12/19	Capability (901382)
	1322				20	X				Z-20			12/13		12/18	12/19	" (902254)
	1323				20	X				R-10			12/13		12/18	12/19	" (902947)
	1391				20	X				S-1026			3/25		6/10	6/19	" V902254
	1393				20	X				S-1027			3/26		6/12	6/18	" test
	1394		2 units to VMD 2 " " L Sabine		20	X				S-1025			5/19		6/13	6/19	" V902947
	1808S	3-11	K Hoglund	3/11	10	X			Hoffman Transitron	1N1956	616210	5-19		1/4			Vendor Comparison
J.K.	1937	4-24	K. Hoglund	4/23	623	X			Tran, Hoff [illegible] Inc, [illegible]	[illegible] 1N1875 [illegible]	616210	5-31		5/2			Vendor Comparison
BNS	2415	2-28	R.J. Kerler	2/9	6	X				HPZ17 HPZ30	616210	2-15	2/11				Parameters + Plots
RG	2566	4-11	R.J. Kerler	4/12	12	X				1N1875	616210	7-6		7/1			Life
HS	2573	(24) 4-13 (24) 5-4	R.J. Kerler	4/13	24+24	X				HPZ 17, HPZ 30	616210	9-25-61		3/2			Life

SEMCOR

ERA-1037

SEMICONDUCTOR TEST RECORD

SPERRY PAGE I

Formerly EF 1059

	PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	OTHER MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST PARAMETER	TEST LIFE	SUMMARY	COMPLETE	REMARKS
	192				18		X			Diff Amplifier		10/16				10/16	Transient Bvance
	789	7/23			100	X				S 127		9/23	9/8		9/23	9/23	Component evaluation
	884	9/4			25	X				S 132		9/19	9/10		9/24	9/24	Design info
	1229 1250	4-22			50	X	x			Blackbox Special			9/4 9/5	4/26	9/23	9/4 9/27	Against 900188 Corr. with Phila.
	1267				6		X			S501			9/13		10/16	10/18	Capability test
	1286				20	X				1N485		2-26/9	11/25		12/5	12/9	" "
	1287	Cancelled —			50	X			—	Special —	Cancelled —					11/12	" " (Test dropped)
	1337		18 to CHJ 2 Hanover test set		20	X				S-127			12/23		1/2	1/3	" " 902818
	1358		1 unit to VMB		8		X			S-500			2/6		4/1	4/4	" "
	1359				3		X			S-501			2/6		4/1	4/4	" "
	1370				26	X				S 127			2/4		3/13	3/17	" 902818B
	1383				2	X				S 127			3/4		3/12	3/14	" Test
	1410				25	X				902 818			[illegible]	/	[illegible]	[illegible]	Life test at 150°C
	1545	11-6	KM Hoglund	/	50	X				S-132	616210	11-19	11/18		11/24	11/24	Initial data R.&I
	1563	11-19	KM Hoglund	11/17	150	X				S-132	616210	12-1	11/26		12/18	12/18	R & I
G.G.	1575	11-20	AA Kaine	11/20	20&20	X	X		Syl	5500-5501	8535104	6-13-61	2/5		2/25	3/2	Cold storage
JK	1796	3-9	PG Hansen	3/9	6	X				S-132	616210	3-27	3/27		3/30	4/2	Parameter
J.K.	1876	4-6	PJ Pearsall	4-3	103	X			Ray-PSI-TI	1N645	359272	9-29		8/10			Capabilities-DS 1078
G.G.	1956	4-28	R. Kerler	4/28	140	X				1N691	616210	6-8(539)	6/5		6/16	6/19	R & I
G.G.	1958	4-28	R. Kerler	4/28	10	X				1N691	616210	1-13	7/27	/			Plots, Elect. Parameters
DJ	2210	10-5	C Johnson	10/7	25		X			V902818	9535104	11-2	10/29				Make measurements
GC	2215	10-8	B. Bissonette	10/9	150	X				(1N692) V907618	616210	10-14	10/12				Receiving Inspection
JM	2290	10-18	R. Erickson	11/17	8	X				S 180	370491	1-6	12/15				Parameter
GC	2313	12-4	B. Bissonette	12/8	960	X				V907618 (1N692)	616210 7392105	12-16	12/15				Electrical Parameters
GC	2392	1-25	B. Bissonette	1/26	375	X				V907618	7342152 616210	2-3	2/2				Component Evaluation
BNS	2486	open	J. Brinda	3/16	1200	X				V907618 & (1N692)	6823152 616210	6-1	6/1			✓	Elect. Parameters

SPERRY I

ERA-1037

SEMICONDUCTOR TEST RECORD

SPRAGUE PAGE I

Formerly EF1059

	PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	Other MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST PARAMETER	TEST LIFE	SUMMARY	COMPLETE	REMARKS
	266				6		X			SB100		1/5				1/5	Heat Storage
	315				20		X			SB100		9/30				9/30	Acceptability
	420	6/26			99		X			L5130 (SB100)		9/28	9/28	9/28	9/28	9/28	Comparison
	519	11/20			50		X		Philco	111350		5/10/8	5/10/8	5/10/8	5/10/8	5/10/8	High Temp Storage
	534	12/17			24		X		Hughes Philco	111350		—	1/15		1/15	1/15	Dip-Solder
	535	12/17/7			36		X		Philco	S3001		2/28/8	7/28	7/28	7/28	7/28	Lead Fatigue, Shock
GG	544	1/2/8			50		X		Philco	111350		5-13-9		3/18	5/4	5/8	5000-hr. Storage 71°C Life
	559	1/17			25		X			L5134		1/29	1/29		1/29	1/29	Parameter distribution
	680	7/9			175		X		Philco	111350		4-19	7/9	2/20			Storage at 84°C.
	956	10/6			10		X			2N501		10/21	10/20		10/24	10/29	Evaluation
	1115	1/29			2		X			2N240			3/18		4/17	4/17	
	1116	1/29			2		X			SB102			3/17		4/17	4/17	
	1122	2/20			3		X			2N159			4/26		4/26	5/22	
	1210	7/3			10		X			LS130			7/16		7/16	7/17	For test lab Units to T. Thomas
	1272	9/17	Units returned to L. Granberg		10		X		Philco	S-3001			10/31		11/5	11/6	Capability (DS 1006B)
	1464		Units returned to R. England		10		X			111350			6/23		9/9	9/9	" (DS 1006B)
	1560	11-14	RM England	11/13	72		X		Philco	111350	359272	4-19	3/2		3/9	3/19	fα fb > 50 mc
J.K.	1626	12-18	RJ Kerler	12/12	8		X			SB271	616210	10/26		10/19			1000 hr. life -100°C
RG	2837	10-5	D.E. Zander	10/17	20		X			2N501	793120	10-6	10/6				Elect. Par.
RI	3069	3-9	R.J. Kerler	3/9	200		X			MD44 (V908567)	9511104	4-4	3/24				Elect. Par.
RI	3129	4-10	R.J. Kerler	4/10	5		X			XT 100	9831104	4-21	4/21				Elect. Par.
RG	3206	6-2	D.W. TASCHNER	6/2	125		X			V910520	793355	6-6	6/5				SHOCK
RI	3220	6-9	K.B. DALAGER	6/9	75		X			XT 100	846223	6-14	6/14				HERM. SEAL
RI	3257	7-7	K.B. DALAGER	7/7	100		X			XT-100	846223 698225 149511	8-15	8/10				LIFE & ENVIR

ERA-1037

SEMICONDUCTOR TEST RECORD SYLVANIA

PAGE I

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST		SUMMARY	COMPLETE	REMARKS
												PARAMETER	LIFE			
29				12	X			Also 9 Other Mfgr	6 1N34 6 1N34A		6/25				6/25	Humidity & Temp Cycling
33				12	X			HUGH.TEC KBR.RAY.TPC	6 1N34A 6 1N58A		10/26				10/26	" " "
46B				6	X			Also Others	1N58A		1/7				1/7	" " "
97				12	X				1N58A		6/30				6/30	" " "
100				6	X				VLI		6/30				6/30	Humidity & Temp Cycling
107A				10		X		Also 12 other Mfgr.	2N94 . 2N94A GT551 . GT847		11/7				11/7	Power Dissipation
155				16	X			Others	10.1N451 6.1N453		5/8				5/8	Pulsed Operation
173				50	X			GE	2N123		4/2				4/2	Temp & Heat Dissipation
206				25	X			Others	D801		8/2				8/2	Reliability
212				15	X			GE	8GT816 7GT845		8/2				8/2	Power Dissipation
224				2 ea.		X		GT	UFC 903.UFC 905		2/25				2/25	Op. Life
233				1		X		Other	2N94A		9/12				9/12	Temp.
527				75	X			HUGH. RR TRANS.CLEV.	D967		—	1/14		8/11	8/11	Vendor Screening
528	12/6			20	X			HUGH.TRANS CBS.CLEV. RR.AMPREX	1N58A		3/16		3/9			Vendor Screening
531	12/6			25	X			HUGH. RR TRANS.CLEV	D967		9-10	1/10		8/15	8/15	Temperature Storage
532	12/6			75	X			HUGH.TRANS CLEV.	D1046		—	6/17		8/8	8/8	Vendor Screening
657	6/26			12		X			2N247		7/30	6/26		9/18	9/18	Accelerated Life
658	6/26			4		X			2N388		7/30	6/26		9/22	9/22	" "
659	6/26			5		X			2N576		7/30	6/26		9/22	9/22	" "
660	6/26			3		X			2N623		7/30	6/26		9/22	9/22	" "
827	8/15			20		X			1326		6-13-61	9/18		10/17	10/17	Capability Against Spec.
842	8/13			6		X			2N625		8/22	8/16		9/12	9/12	Parameter Distribution
858 A B C	8/22			75		X		GT.RAY	31 AY 903214 31 Y 900788 33 Y 903213		11/11	9/26		11/18	12/5	Failure Analysis
997	10/23			17		X		GT	V903214		7-10	11/19		12/16	12/16	" "
998	10/23			19		X		GT	V903213		7-10	11/3		12/4	12/4	" "
1036				17	X				D989			2/20		5/13	5/13	Hi-Conduction type
1037				19	X				D967			2/20		5/13	5/13	

Formerly EF1059

SYLVANIA I

ERA-1037

SEMICONDUCTOR TEST RECORD

SYLVANIA

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	OTHER MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
1039				6	X	X			GT 859			10/27		6/5	6/5	Lost + Found 6-5-57
1040				5+5		X			GT759+760			1/4		3/4	4/30	Error - See GT
1042				65		X			GT845				2/5	3/18	3/18	
1043				60		X			GT903				2/4	3/18	3/18	
1044				60		X			GT905				2/4	3/18	3/18	
1045				60		X			GT760							MISSING
1046				6		X			GT901			2/25		2/4	5/13	
1050				38	X				D966			1/7		2/4	5/13	
1051				40	X				D793			1/24		2/3	2/3	
1080				17	X				D989			3/4		3/4	5/22	Pt. Contact type
1094	1/5			6		X			GT902			3/4		3/4	5/23	Units sent out via C.A.S.
1105	1/11			42		X			UFC 903			1/9		1/11	5/22	Removed From UFC #5
1110	1/16			72		X			UFC 905			1/15		2/12	2/12	" " " "
1117	1/30			15		X			GT 906			1/31		2/10	4/29	Return to Valenty
1131	3/18			24		X			UFC 903			3/26		3/27	4/2	From UFC #4,7&8
1132	3/18			99		X		GT	UFC905			3/25		3/26	4/2	" " " " "
1156	4/17			55		X			UFC 903			4/29		4/29	5/24	" " #2,4,6,8,11
1157	4/17			85		X			UFC 905			4/29		4/29	5/23	" " #4,6,8,11
1158	4/17			110		X			2N94			5/8		5/8	6/19	" " #2,6,11
1160	4/17			114		X			UFC 905			5/7		5/7	5/13	" " #2
1186	5/4			24		X			UFC 903			6/7		7/22	7/25	Critical vs Non-critical units
1184	5/10			50		X			900755B			6/20	5/20	7/23	7/24	
1194	6/4			10		X			UFC 903			6/4		6/4	6/14	From UFC #14
1195	6/4			47		X			UFC 905			6/7		6/10	6/14	" " " 14
1197	6/10			14		X		GT	UFC 903			10/1		10/24	10/25	Leakage vs Temp
1198	6/14			12		X			1067			8/29		10/17	10/18	New case - JETEC 30

Formerly EF 1059

SYLVANIA II

ERA-1037

SEMICONDUCTOR TEST RECORD TEXAS·INSTRUMENTS PAGE I

Formerly EF 1059

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST PARAMETER	TEST LIFE	SUMMARY	COMPLETE	REMARKS
296				29		X			953		4/1				4/1	Heat
599	3/31			200	X			Trans	1N660		4/17	4/17		5/17	5/17	Mechanical Shock
663	7/2			6		X			X-281		7/30	7/14		8/2	8/11	Pulse response
674	7/7			15		X			2N341		7-25	7/30		9/24	9/24	Suitability as T.I. 953 replacement.
801	7/29			24		X			TI952		8/19	8/11		9/19	9/19	Parameter distribution
810	8/4			100		X			2N623		8/19	8/14		9/23	10/2	" "
818	9/5			15	X			Other	1N645		—	1/16		2/16	2/16	Surge current
831	8/22			15	X				1N645		8/26	8/26		9/18	9/18	Component evaluation
857	8/22			11	X			Other	V902261-6		11/11	9/22				Failure analysis
886	9/4			21	X			Ray Philco	1N645		9/19	9/11		9/23	9/23	Initial data
905	9/16			10		X			2N623		9/29	9/19		10/2	10/2	To Confirm Instabilities
916	9/19			20		X			2N1046		10/6	10/6		10/27	10/27	Rec. insp.
924	9/19			50	X				650 CO		10/6	10/3		10/29	10/29	" "
939	9/30			1		X			2N1046		10/20	10/15		10/21	10/21	Failure analysis
951	10/2			6		X			2N559		10/21	10/20		10/30	10/30	Evaluation
1025	11/1			6		X			2N248			1/4		3/4	4/30	
1041	11/23			3		X			X114C					2/4	2/4	
1173	4/22			6ea.		X			2N337 2N338			5/1	5/1	5/1	6/19	
1181	4/29			6		X			X196			5/15		5/15	6/19	
1196	6/10			16		X			X194			7/2		7/3	7/15	Against 2N123 (901867)
1220	7/15			10	X				1N646			7/19		7/19	9/23	Capability test
1274	9/18			3ea.	X				1N660 1N661			10/4		10/22	10/23	" "
1371	—	Cancelled See 384		20	X	—	—	—	1N660 (C02)	Cancelled	—	—	—	—	9/17	" " (902818B)
1373		units returned to L. Granberg		25	X				1N660			2/26		3/6	3/10	" "
1384				20	X				(C02) 1N660		2-26-9	3/3		3/17	3/17	" " 902818B
1407				20	X				D24			3/26		/	/	" "

TEXAS·INSTRUMENTS

ERA-1037

SEMICONDUCTOR TEST RECORD

T. P.

PAGE I

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	OTHER MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
29				6	X			IRC/Kemtron Gahagan	1N34A		6-25				6/25	Humidity & Temp cycling
33				6	X			Kemtron	1N56		10-26				10/26	" " " "
46				24	X			IRC	1N58A-T3-T6		1-7				1/7	" " " "
46B				6	X			Federal	T6G		1-7				1/7	" " " "
97				21	X				1N58A		6-30				6/30	" " " "
100				20ea	X				X268' -X268²		6-30				6/30	" " " "
120				18	X				1N191-1N92-1N93		10-10				10/10	Comparison

T. P.

ERA-1037

SEMICONDUCTOR TEST RECORD

TRANSITRON

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	OTHER MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
33				6	X			Also Others	T1		10/26				10/26	Humidity & Temp Cycling
46				12	X			Also Others	6- S144 6- 1N58		1/7				1/7	" " "
46B				12	X			Also others	6- T6G 6- S29		1/7				1/7	" " "
85				1080 50	X			Also Others	10 T5G-T3G-T7G T12G-T16G		4/19				4/19	" " "
100				2082	X			Also Others	T6G-S29G		6/30				6/30	" " "
101				28	X			Hughes	1N143·T5G·T8G		3/12				3/12	Operational
107A				19		X		Others	2·2N92-7 2N66·4 2N91 1-X128-5·2N43		10/10				10/10	Power Dissipation
107A				37	X			Others	5 T16G·6 1N143·4 T8G 6 T12G·6 T5G 6 T7G·4 T3G		10/10				10/10	" "
126A				33	X			Hughes	23 S180G 10 T16G		2/2				2/2	Reliability & Temp
166				24	X			others	S144G		3/12				3/12	Comparison
231				10		X		CBS	T17G		12/6				12/6	Operational Life
277				28	X			RR	S180G		1/15				1/15	Humidity & Temp Cycling
313				20	X				S359G		9/27				9/27	Capability DS1004A
347				14	X			Other	SG228		3/8				3/8	Stability Char.
369				320	X			Hughes	1N118		4/4				4/4	Comparison
378				50	X			Hughes	1N118		6/26				6/26	Vibration
386				50	X			Others	S430G		10/11				10/11	Shelf Life
417	6/28			199	X				S430G		7/12	7/12		7/12	7/12	Forward Current
424	7/1			300	X				S430G		9/13	9/13	9/13	9/13	9/17	Elec. Temp. Vib. Shock. Life
437	7/11			50	X				1N118		8/29	8/29	8/29	8/29	8/29	Vibration Shock·Soldering
453	8/26			20	X			Clev.	1N207		3/6/8	3/6/8	3/6	3/6	3/6/8	High Temp Under Pulse
454	7/31			360	X				S430G		8/7	8/7		8/7	8/7	Production Handling Method
523	12/2			100	X			Other	1N1318		—	8/7	8/7	8/7	8/11	Vibration Life
624				75	X			HUGHES CLEV	6589		—	1/16		8/15	8/15	Vendor Screening
527				76	X			Other	S333G		—	1/14		8/11	8/11	" "
528	12/6			20	X			Other	S144G		3/16		3/9			" "

TRANSITRON I

ERA-1037

SEMICONDUCTOR TEST RECORD — TUNG SOL

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
820	8/11			10		X			DS1005D, EF1059-432		8/26	8/26		10/28	10/28	2nd. Source G.E. 4JD1A70
855	8/26			25		X		other	DS1005		9/9	9/9		9/29	9/29	Hermetic seal
856	8/25			20		X		other	DS1005		7/20		6/5			High-temp. storage (85°C)
1006	5/21			6		X			DR 152					6/10	6/10	Data lost til 6-10-57
1007	5/21			2		X			DR 176							
1102	1/10			12	X				900181			4/24		4/29	5/22	
1103	1/10			19	X				900340			4/25		4/25	5/22	
1233	7/29	Returned		6		X			XT100			8/9		8/9	8/23	Capability Test
1234	7/29	to		6		X			XT101			8/6		8/6	8/23	" "
1235	7/29	Tung-Sol		6		X			XT102			8/9		8/9	8/23	" "
1247	8/26			26		X			Unknown			8/30		10/17	10/18	Helium leak & Detergent
1290				25		X			Unknown			11/25		12/10	12/11	Capability test
1315				100		X			903209A			1/2		1/24	1/24	Capability & Lifetest 70°C 500hr Hermetic seal RbI Verification
1316				100		X			903210A			1/2		1/24	1/24	Same as above
1317				100		X			903211A			1/2		1/27	1/28	" " "
1319				5	X				XD101			1/8		1/28	1/29	Capability test
1320				5	X				XD100			1/8		1/28	1/29	" " 900340
1350				10	X				2N382			1/2		2/11	2/12	" " P_z vs T_j
1351				25		X			904052C			1/3		2/21	2/24	Same as above
1352				15		X			904053A			1/7		2/21	2/24	" " "
1360				25		X			Unknown			1/28		3/5	3/6	Hermetic seal-Comparison
1398				20		X			904053/052			5/8		4/22	4/27	Capability against V904052
1402				20		X			900226			4/11		5/1	5/6	" " V902226
1403		8 units to R. Lorenz		20		X			903210A			5/6		6/30	7/11	" " V903210A
1432		Units returned to R. England		10		X			DS1005D			5/8		5/16	5/22	Suitability for spec.
1440		Units to AAK		20		X			904433			5/14		6/4	6/6	Capability 904433

Formerly EF 1059

TUNG SOL

ERA-1037

SEMICONDUCTOR TEST RECORD WESTERN ELECTRIC

PAGE I

PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	OTHER MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
275				25		X			GA 53242		11/8				11/8	Evaluation
305				20		X			GA 53242		4/11				4/11	Temp storage
624	5/12			24		X			2N559		7/30	7/16		9/9	9/16	Determine switching times
662	6/26			25		X			2N559		7/30	7/8		7/9	8/1	Parameter distribution
665	7/2			24		X			GF45017		7/2	7/2		7/8	7/8	Parameter distribution
673	7/7			10		X			GF45017		7/28	9/21		9/24	9/24	" "
697	7/23			10		X			2N560		7/30	7/25		7/25	8/14	" "
788	7/23			25		X			2N559		8/19	7/29		9/24	9/24	" "
791	7/25			50		X			GA53242		4/19		7/25	9/24	9/24	Storage life 84°C
821	8/11			10		X			GF45017		8/29	8/13		8/26	9/1	Hermetic seal
839	8/13			2		X			2N559		8/22	8/19		9/16	9/8	Confirm data
851	8/18			25		X			GA52830		8/28	8/23		9/16	9/19	Component evaluation
862	8/25			2		X			2N559		9/5	9/4		9/22	9/22	Failure analysis
864	8/28			25		X			2N559		9/19	9/18		11/25	11/25	Data for circuit design
868	9/22			25		X			2N559		9/25	9/25		1/22	1/22	Design info
919	9/19			174		X			2N559		11/21	10/2		10/9	10/9	Rec insp.
934	9/26			2	X				1N696		10/20	10/15		10/21	10/21	Failure analysis
957	10/6			9		X			2N559		10/20	10/16		10/25	10/25	" "
971	10/14			28		X			GA 53242		10/30	10/21		11/20	11/20	Meas. fα FB
972	10/14			75		X			2N560		11/4	10/30		12/19	12/19	Rec. insp.
977	10/14			3100		X			2N559		12/29	12/29		1/7	1/21	" "
983	10/20			7		X			2N559		11/5	11/3		12/1	12/1	Failure analysis
987	10/21			10		X			GA 53242		11/7	11/7		1/2	1/2	Initial data
1401		Units returned to L Granberg		27		X			GA53242			3/11		3/24	3/25	Hermetic Seal test
1455		Units returned to R Kerler		23		X			2N559			6/9		8/22	8/22	Pulse response test
1481	10-23	RM England	10/23	90		X		G.E. Philco	5 TYPES	359272	4-19	12/15		12/11	12/11	MW/°C

WESTERN ELECTRIC

Formerly EF 1059

ERA-1037

SEMICONDUCTOR TEST RECORD — WESTINGHOUSE

PAGE I

	PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	OTHER MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
	107A				3		X			2N54		10-10				10/10	Power dissipation
	859	8-25			12	X				302A		9-30	9/29		10/27	10/27	Design data.
	923	9-19			6	X				304A		10-6	9/30		10/8	10/8	R&I
	974	10-14			1	X				302A		10-21	10/20		11/5	11/5	FA
	975	10-14			7	X				304A		10-21	10/20		11/5	11/5	FA
Formerly EF1059	1005	10-15			2		X			XD5082			3/18		4/30	4/30	
	1534	10-30	KM Hoglund		2	X				302A	616210	11-18	11/12		11/26	11/26	FA
	1546	11-6	KM Hoglund		15	X				1N220 or 320-0	616210	11-24	11/21		12/12	12/12	Plots
JK	1643	12-23	KM Hoglund	12/23	20	X				1N1186	616210	1-12	1/5		1/23	1/23	Elec. para.
JK	1676	1-20	H Frazier	1/20	25	X				329F	359281	To 1846 3-23	2/4		2/10	2/16	" "
	1772	2-27	AA Kaine	2/26	10	X				X806	613120	6-13-61	3/16		4/21	4/24	Parameter
GG	1837	3-19	KM Hoglund	3-19	36	X			IRC-GE	1N1304	616210	3-30	3/27		3/30	4/3	Plots
J.K.	1846	3-23	HN Frazier	3-23	75	X			IRC-GE	3297	359281	10-5		9/29			1000 hr life test
G.G.	1859	3-30	KM Hoglund	50	60	X			Trans-GE Mot-Auto	1N1670 1N538-1N1220	616210	6-27		6/9	(60)		Vendor Comparison
G.G.	1860	3-30	KM Hoglund	60	60	X			Trans-GE Mot-Auto	1N1670 1N538-1N1220	616210	(5) 7-10 6-3	5/25		7/10	7/16	" "
GG	1872	4-6	KM Hoglund	4-3	50	X			GE-Mot Auto-Trans	1N1220	616210	(20) 5-14 (28) 6-27		6/9	(60)		" "
J.K.	2009	5-22	K. Hoglund	5/22	36	X			G.E. Int. Rect.	W302D	616210	3-15		3/3			Vendor Comparison
JM	2188	~~9-25~~	~~B. Bissonette~~	~~9/28~~	~~130~~		X			~~2N559~~	~~7260-152~~	~~10-1~~	10/1				~~Receiving Inspection~~
~~DJ~~	~~[illegible]~~	~~[illegible]~~	~~B. Bissonette~~	~~10/7~~	~~100~~		~~X~~			~~2N1072~~	~~616210~~	~~10-15~~	~~10/14~~				~~Receiving Inspection~~
BNS	2608	4-29	D.L. Sandstrom	4/26	6+12	X			G.E.-C.D.	1N1202	659170	11-29	11/29				Life, HST, Shock
JK	3191	5-22	E.P. DEEB	5/22	3+10		X		FAIR.	2N1051-2N915	779293	6-21	5/24				ELECT. PAR.
JK	3305	8-10	R.M. ENGLUND	8/10	9	X			GI-4	1N1202 (V908293)	698225	8-24-61	8/20				IR vs TIME
JK	3316	8-17	E.P. DEEB	8/15	20		X										

WESTINGHOUSE

ERA-1037

SEMICONDUCTOR TEST RECORD

MISCELLANEOUS PAGE I

	PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
	12				10		X		Bell-Lab	A1698-A1768		2-29				2/29	Comparison
	18				10		X		Detectron			5-16				5/16	Characteristic
	29				48	X			Kemtron			6-25				6/25	Humidity & Temp. cyc.
	33				18	X			KemTron	K63		10-26				10/26	" " "
	107A				3/17/2		X		Hydro Aire GP/NU	JP1 2N98A / T348		10-10				10/10	Power dissipation
	664	7-2			23	X			Bell-Lab	BTL 2030		7-30	7/9		8/7	8/7	Capability
	1014	7-9			6	X			Bogue	1N316							
	1015	7-9			6	X			"	1N317							
	1016	7-9			5	X			"	1N318							
	1201	6-13			2				Eckert Mauchly Potter				6/13	6/14	6/14	6/17	Mag. tape read-write heads
	1444				25	Heat Sink			Bircher Corp	None			6/5		9/9	9/14	Dissipation increase with use of heat sink
	1624	12-18	KM Hoglund	12/18	16	X			Shockley	4N50-DL	618210	2-9	2/5		2/18	3/5	Elec. para.
	1662	1-12	EP Deeb	1/12	100 100	X	X		Several	Several	8532104		2/13		2/23	2/27	Evaluation, HST
JK	1783	3-4	R.H. Ness	3/2	25	X			Auto mfg.	R 3.9	359281	3-27	3/10		3/23	3/30	Reliability
JK	1853	3-27	R.H. Ness	3-25	25	X			Auto.	R 3.9	359281	7-13		7/10			Operating life test
GG	1859	3-30	KM Hoglund	3-27	50	X			Auto.-GE-Mot. West.-Trans	1N1570 1N538-1N1220	616210	6-27		6/9	(60)		Vendor Comparison
GG	1860	3-30	KM Hoglund	3-27	60	X			Auto-GE-Mot West-Trans	1N1570 1N538-1N1220	616210	(5) 7-10 6-3	5/25		7/10	7/16	" "
GG	1872	4-6	KM Hoglund	4-3	50	X			Auto/GE-Mot Trans-West	1N538	616210	(20) 5-14 (28) 6-27		6/9	(60)		" "
	1937	4-24	K. Hoglund	4/23	623	X			Auto, Hoff., Tran, PSI, IRC, WE, U.S. Sem.	R 8.2	616210	5-31		5/2			Vendor Comparison
DS.	1953	4-27	P. Pearsall	4/27	30		X		Industro	DS 1005 H	359272	5-5	5/2		5/19	5/25	Plots & data
	1993	5/12	K. Hoglund	5/12	10	X			Shockley	4N50AD	616210	5-22	5/22				R∨I
D.S.	2007	5-20	R. Ness	5/20	10	X			I.T.&T.	ZB 3.9	359281	6-25	6/18		6/30	7/6	Electrical Parameters
A.R.	2069	6-30	R. Oljinad	6/29	350	Thermistors			Victory Engr. Corp	241A20	3704BP	7-22	7/7				Low or Temp. Exposure
G.G.	2073	7-6	K. Hoglund	7/6	25		X		Mpls-HW	2N1202	616210	7-6		7/6			Storage Life Test
J.K.	2078	7-13	K. Hoglund	7/13	10	X			Sarkes-Tarzian	40X3P, 30X3P	616210	8-14	8/14				Elect. Parameters
R.P.	2086	7-13	K. Hoglund	7/13	6	X	Photo		Nucleonic Products	TP-50	616210	(3) 8-25 (3) 8-26	8/26				Elect. Parameters, Plots

ERA-1037

SEMICONDUCTOR TEST RECORD Miscellaneous II

PAGE

	PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
GC	2096	7-20	K. Hoglund	7/22	20	X			Shockley	4N20D, 4N30AD	616210	7-31	7/31				R & I
JM	2118	8-4	K. Hoglund	8/11	10		X		Mpls-HW	2N575A	616210	8-21	8/20				R + I
JK	2164	9-2	K. Hoglund	9/4	5	X			C. D.	1N764	616210	9-10	9/9				Elect. Par.
	2273	11-3	R. Erickson	11/3	20	X			Qutronix	Q6-100, Q5-100	370491	11-9	11/5				Elect. Par.
GC	2343	12-22	R.J. Kerler	12/22	12	X			Colombos	1N538	616210						Vendor Evaluation
GC	2427	2-15	R.F. Rohde	2/16	40	X			Silicon Trans. Corp.	1N645	779221	5-26		4/29			Qual. Test & Plots
GC	2445	2-23	R.F. Rohde	2/22	50	X			Silicon Trans. Corp.	1N646	779221	5-26		4/29			Qual. Test & Plots
BNS	2490	3-15	R.J. Kerler	3/16	200	X			Erie	ED 1961 (V907302B)	616210	(50) 4-18 (150) 5-25	4/14	3/16			Life, HST, Shock, Par.
RG	2568	4-11	R.J. Kerler	4/12	20	X			Continental	CD 2263	616210	5-19	5/17				Elect. Par.
RG	2569	4-11	R.J. Kerler	4/12	5	X			Continental	CD 3345	616210	6-13	6/10				Elect. Par.
HS	2604	4-29	R.A. Erickson	4/25	50	X			Kemtron	1N87A	370491	5-30	5/20				Elect. Par., HST, Shock, Lead Fatigue
BNS	2606	4-29	R. Hackel	4/25	9	X			N-Z Assy	9717826	616317	6-23	6/22				Elect. Par.
BNS	2608	4-29	D.L. Sandstrom	4/26	12+6	X			West. C.D.	1N1202	659170	11-29		11/29			Life, HST, Shock
RG	2675	5-24	T.J. Maley	5/24	4				Birtcher	4 Types	9812104	3-13	3/13				Thermal Conductance
RG	2677	5-31	O.G. Johnson	5/24	6	X			Solitron	CER-69	626220	7-13	7/7				Elect. Par. vs Temp., HST
DO	2756	8-5	R.M. Englund	8/5	25	X			Standard Rectifier	1N1202	659170	9-12	8/12				Elect. Par.
HZ	2866	10-28	E.P. Deeb	10/28	11	X			Microwave Associates	1N903	889241	11-29	11/8				Elect. Par.
HZ	2871	11-1	E.P. Deeb	11/1	200	X			Microwave Associates	1N905	889241	11-22	11/8				Elect. Par.
WC	2885	11-11	J.W. Lockhart	11/11	2	X			RRU	Experimental	844201	11-11	11/11				Diode Assy.
RR	2916	12-7	D.A. Oines	12/7	150	X			Erie	ED1961 (V907302B)	841531		1/10	4/17			Life, Envir.
HZ	2924	12-8	E.P. Deeb	12/8	200+11	X			M.A.-(Fair.)	1N905 - (FD162)	889233	1-6	1/5				Elect. Par.
HZ	2933	12-15	E.P. Deeb	12/15	10		X		STC	2N1490	889233	3-2	1/20				Elect. Par.
RI	2948	12-23	R.M. Englund	12/23	6+6		X		C.P. Clare	908635- 908637	793120	1-23	1/19				Elect. Par.
JK	2980	1-20	D.A. Oines	1/20	4	X			Columbus	1N 2156	9511104	1-26	1/25				F & R Plots
RR	3017	2-10	D.L. Sandstrom	2/10	100+100	X			C Erie	V908631- V908664	844454			11/20			Standard Life
RN	3024	2-13	J. Casement	2/14	10				RRU	Diodes on board	889213						Thermal Res. of Pot. Compound

Miscellaneous II

ERA-1037

SEMICONDUCTOR TEST RECORD Miscellaneous

	PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST PARAMETER	TEST LIFE	SUMMARY	COMPLETE	REMARKS
JK	3040	2-20	R.W. Jensen	2/23	1+1	X			RRU	Resistor + Diode Block	889233	CANCELED					R + I_R
JK	3041	2-21	R.W. Jensen	2/23	3	X			RRU	Diode Block	889233	2-27	2/26				I_R
RR	3093	3-17	E.P. Deeb	3/17	300	X			M.A.	MA 4412 (907821 B)	889233			8/18	1		Standard Life
RI	3137	4-14	D.E. Zander	4/14	50	X			M. A.	—	699234	5-12	5/10				Elect. + Mach. Par.
RI	3148	4-20	D.L. Sandstrom	4/20	50+64	X			M.A.-(Fairchild)	V 908650 B	960800	5-23	5/19				Envir.
MB	3165	5-3	D.E. Zander	5/3	42	X			N.T.I.	—	699234	5-25	5/24				Elect. Par. + Shock
RI	3170	5-9	D.A. OINES	5/9	100		X		HONEYWELL	2N1502	149511	5-25	5/24				ELECT. PAR.
MB	3171	5-9	E.P. DEEB	5/9	200	X			M.A.	V907821D	889233						ELECT. PAR.
RR	3171S	9-13	E.P. DEEB	9/13	125	X			M.A.	MA4412(907821)	779293						STANDARD LIFE
RI	3190	5-22	E.P. DEEB	5/22	25+100	X			M.A-M.S	V907822C	779293	6-19	6/14				ELECT. PAR.
MB	3218	6-9	D.E. ZANDER	6/9	25	X			N.T.	—	698225	6-20	6/16				C_s & t_{rr}
RI	3238	6-20	E.P. DEEB	6/20	25+98	X			MA-MS	907822C	779293	7-25	7/25				ENVIR.
MB	3241	6-23	E.P. DEEB	6/23	25	X			M.A.	MA 4412	779293	8-16	8/15				ELECT. PAR. & ENVIR
MB	3277	7-18	B.N. SVENDSEN	7/18	304	X			VARIOUS	V908202	149511	10-27-61 BOB NELSON	8/4				ELECT. PAR.
JK	3296	8-1	D.E. ZANDER	8/1	10+6	X			BRADLEY SYNTRON	1N1202	698225	8-10-61	8/9				PLOTS & HST
MB	3314	8-16	B.N. SVENDSEN	8/16	30	X			DICKSON	1.5Z30D, 1.5Z45D D10330E, D103300	149511	9-19	9/13				ELECT. CHAR.
MB	3336	8-31	K.B. DALAGER	8/31	10	X			NATIONAL	908202	998140	9-26	9/7				V_F
RI	3392	10-3	K.B. DALAGER	10/3	4			X	HONEYWELL	3N51(912306)	998140	10-12-61	10/11				ELECT. PAR.
MB	3418	10-18	E.P. DEEB	10/18	25	X			N. T.	(907823)	779293						ENVIR.
JK	3435	11-1	D.A. OINES	11/1	25		X		HONEYWELL	2N1658(907304)	946211	11-13-61	11/13				ELECT. PAR.
RI	3436	11-2	R.F. McGOWAN	11/2	2	X			RRU	EXP.	779293	1-19	12/1				HUMIDITY
JK	3451	11-20	R.M. ENGLUND	11/20	18	X			ERIE	ED 2941(907806)	698225	11-30	11/29				ELECT. PAR.
RI	3455	11-24	E.P. DEEB	11/24	200 25	X			M.A. R.S.I.	MA 4412 1N905 (907821D)	779293						ELECT. PAR.
JK	3457	11-28	D.A. OINES	11/28	25		X		HONEYWELL	2N1658(912899)	946211	1-16	1/15				THERMAL RESISTANCE
JK	3458	11-28	K.B. DALAGER	11/28	2			X	HONEYWELL	3N51(912306)	998160	1-3	12/28				THERMAL RESISTANCE
RI	3490	12-27	R.M. Englund	12/27	7		X		SSPI	2N1882S (908696)	698225	1-22	1/20				Elect. Par.

ERA-1037

SEMICONDUCTOR TEST RECORD

Miscellaneous IV PAGE

	PX 72000-	SAMPLES RECEIVED	REQUESTED BY	DATE	QUANTITY	DIODE	TRIODE	TETRODE	MFGR.	TYPE NO.	ACCOUNT OR PROJECT NO.	SAMPLES RETURNED	TEST: PARAMETER	TEST: LIFE	SUMMARY	COMPLETE	REMARKS
JK	3502	1-5	R.M. England	1/5	150	X			N.T.	G229 (907802)	698225		1/31				Envir.
JK	3506	1-8	R.M. England	1/8	5 2	X			Bradley West.	1N1202 (908293)	698225	1-15	1/15				Plots + Vf
JK	3514	1-11	R.M. England	1/11	200	X			N.T.	G202 (907828)	698225	1-16	1/15				Envir.
RG	3553	2-13	H.N. Short	2/13	250	X			Toschiba	EM90	149501	3-15	3/14				Envir.
R.S	3594	4-3	D.A. Oines	4/3	2	X			Honeywell	2N1658 (912899)	946211						Temp. VS air Velocity

Miscellaneous IV